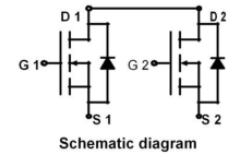


20V N+N Channel Enhancement Mode MOSFET

Description

The AP8205S uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V.

This device is suitable for use as a Battery protection or in other Switching application.

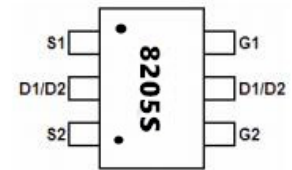


General Features

$V_{DS} = 20V, I_D = 6A$

$R_{DS(ON)} < 20.5.m\Omega @ V_{GS}=4.5V$

$R_{DS(ON)} < 27.m\Omega @ V_{GS}=2.5V$



Application

Battery protection

Load switch

Powermanagement



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP8205S	SOT-23-6L	8205S	3000

Absolute Maximum Ratings@ $T_j=25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_A=25^\circ C$	Drain Current, $V_{GS} @ 4.5V^3$	6	A
$I_D @ T_A=70^\circ C$	Drain Current, $V_{GS} @ 4.5V^3$	4.8	A
IDM	Pulsed Drain Current ¹	26	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	2	W
	Linear Derating Factor	0.016	W/°C
TSTG	Storage Temperature Range	-55 to 150	°C
T_j	Operating Junction Temperature Range	-55 to 150	°C
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	62.5	°C/W



20V N+N Channel Enhancement Mode MOSFET

Electrical Characteristics@T_j=25°C(unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	20	-	-	V
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V, I _D =6A	-	20.5	27	mΩ
		V _{GS} =2.5V, I _D =4A	-	27	37	mΩ
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250uA	-	0.75	1.2	V
g _{fs}	Forward Transconductance	V _{DS} =10V, I _D =6A	-	6	-	S
IDSS	Drain-Source Leakage Current	V _{DS} =20V, V _{GS} =0V	-	-	25	uA
	Drain-Source Leakage Current (T _j =70°C)	V _{DS} =20V, V _{GS} =0V	-	-	250	uA
IGSS	Gate-Source Leakage	V _{GS} =±12V, V _{DS} =0V	-	-	±100	nA
Q _g	Total Gate Charge ²	I _D =6A	-	11	17.6	nC
Q _{gs}	Gate-Source Charge	V _{DS} =16V	-	1.1	-	nC
Q _{gd}	Gate-Drain ("Miller") Charge	V _{GS} =4.5V	-	4.1	-	nC
td(on)	Turn-on Delay Time ²	V _{DS} =10V	-	4.2	-	ns
t _r	Rise Time	I _D =1A	-	9	-	ns
td(off)	Turn-off Delay Time	R _G =3.3Ω, V _{GS} =10V	-	23	-	ns
t _f	Fall Time	R _D =10Ω	-	3.5	-	ns
C _{iss}	Input Capacitance	V _{GS} =0V	-	570	910	pF
C _{oss}	Output Capacitance	V _{DS} =20V	-	90	-	pF
C _{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	85	-	pF
R _g	Gate Resistance	f=1.0MHz	-	1.6	2.4	Ω
V _{SD}	Forward On Voltage ²	I _S =1.7A, V _{GS} =0V	-	-	1.2	V
t _{rr}	Reverse Recovery Time ²	I _S =6A, V _{GS} =0V, dI/dt=100A/μs	-	21	-	ns
Q _{rr}	Reverse Recovery Charge		-	14	-	nC

1.Pulse width limited by Max. junction temperature.

2.Pulse test

3.Surface mounted on 1 in² copper pad of FR4 board, t ≤10sec ; 135 °C/W when mounted on Min. copper pad.

20V N+N Channel Enhancement Mode MOSFET

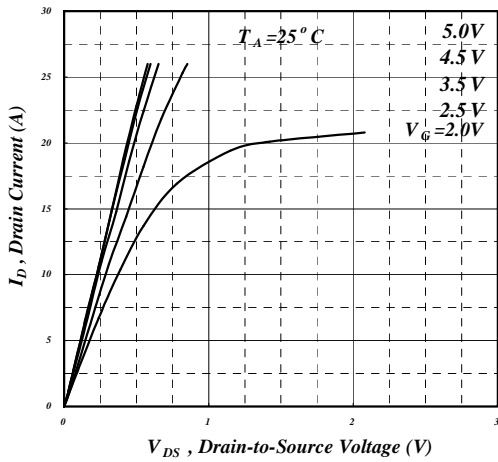


Fig 1. Typical Output Characteristics

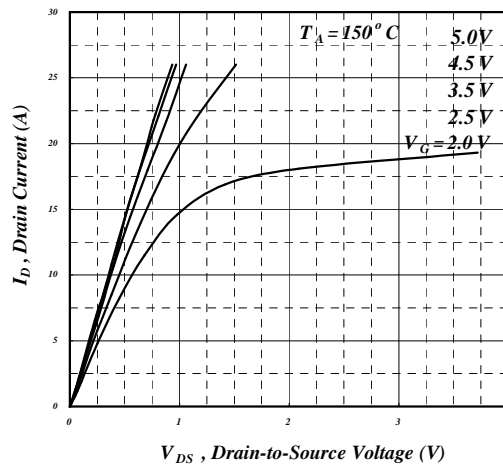


Fig 2. Typical Output Characteristics

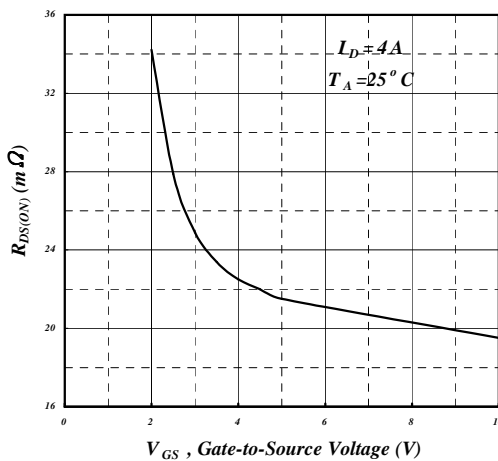


Fig 3. On-Resistance v.s. Gate Voltage

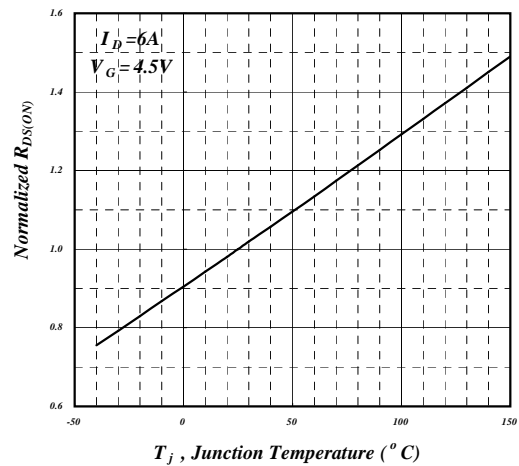


Fig 4. Normalized On-Resistance v.s. Temperature

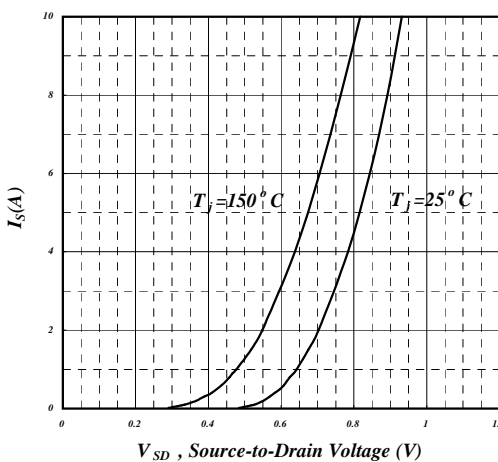


Fig 5. Forward Characteristic of Reverse Diode

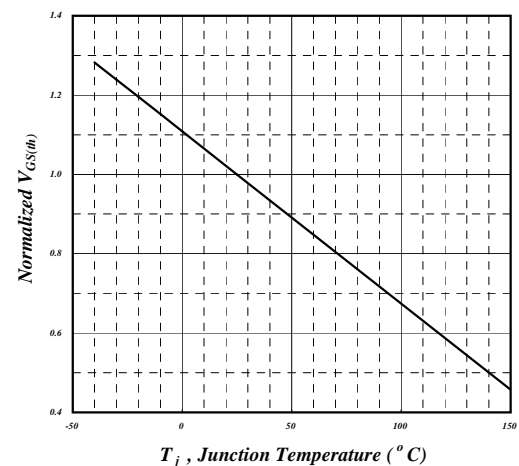


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



20V N+N Channel Enhancement Mode MOSFET

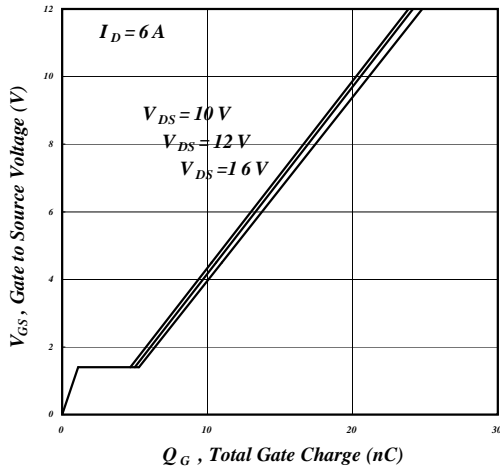


Fig 7. Gate Charge Characteristics

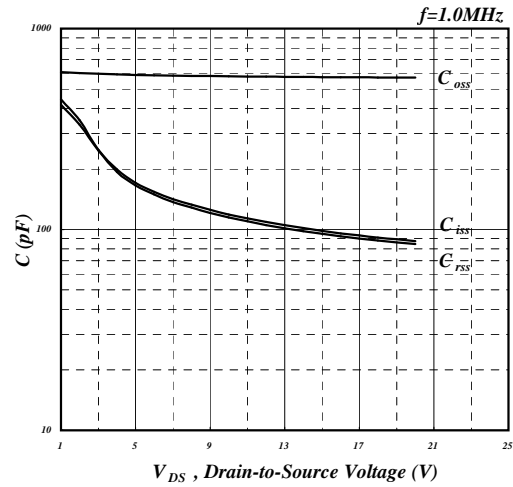


Fig 8. Typical Capacitance Characteristics

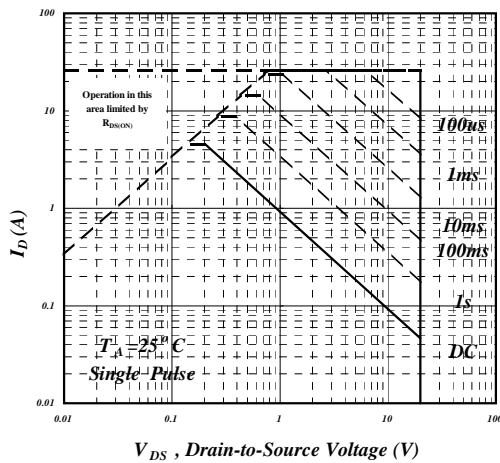


Fig 9. Maximum Safe Operating Area

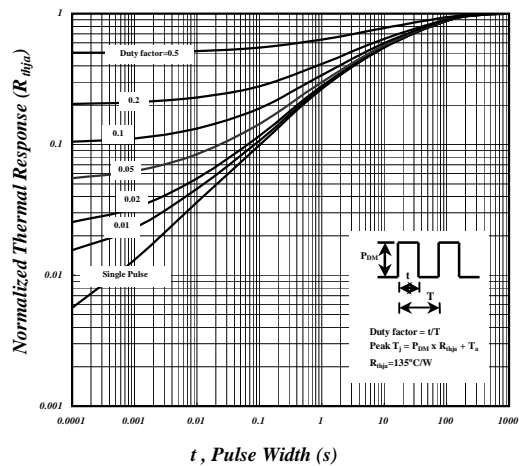


Fig 10. Effective Transient Thermal Impedance

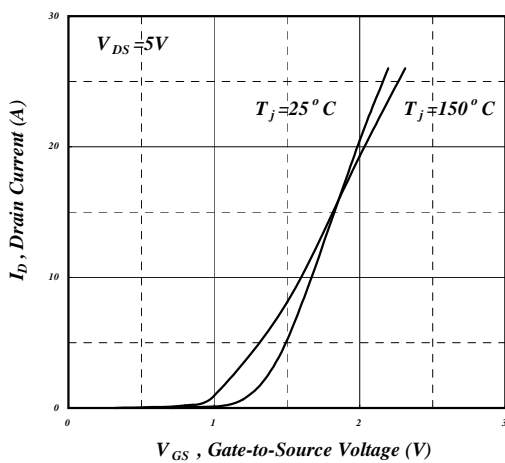


Fig 11. Transfer Characteristics

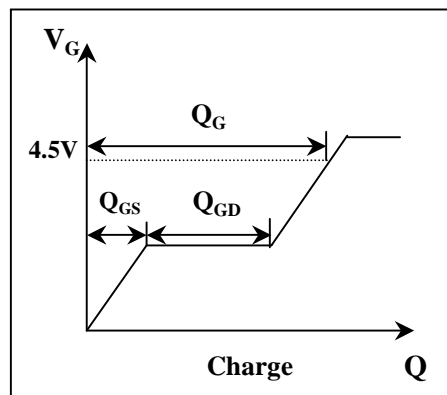
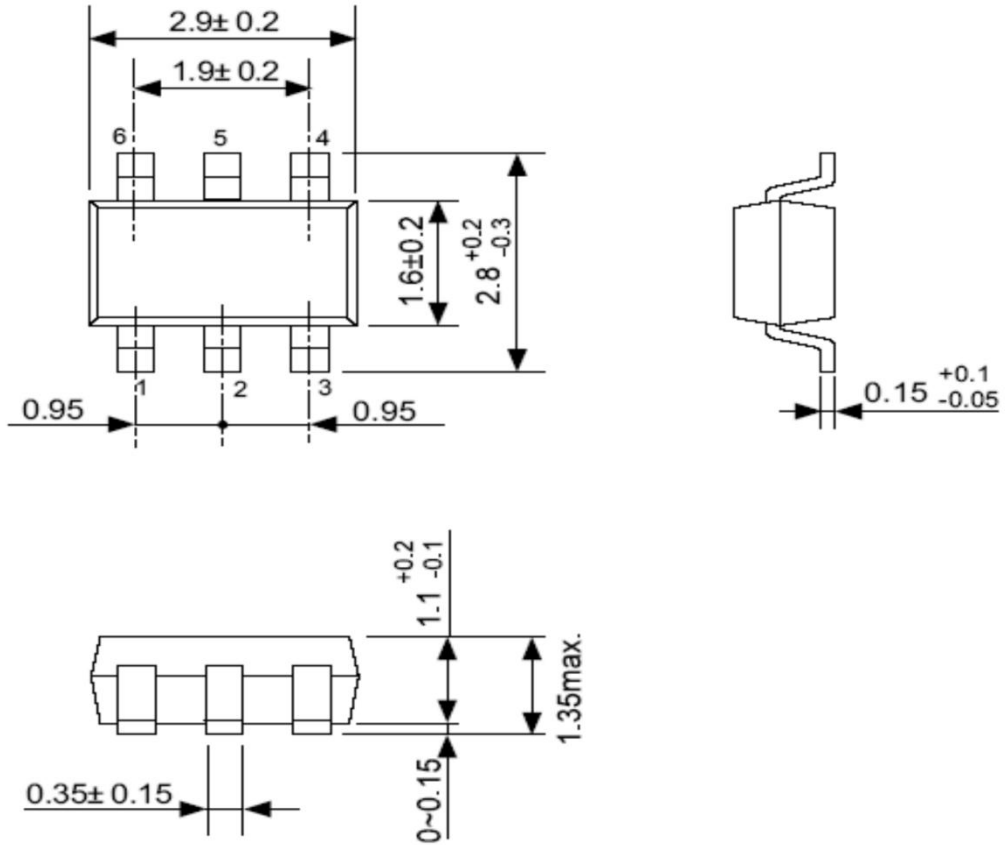


Fig 12. Gate Charge Waveform

SOT23-6 PACKAGE INFORMATION



20V N+N Channel Enhancement Mode MOSFET**Attention**

- 1, Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.
- 2, APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.
- 3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- 4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- 5, In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- 6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.
- 7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- 8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the APM Microelectronics product that you intend to use.